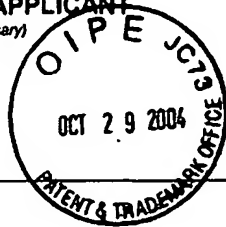


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Application Number	10/081,439
Filing Date	February 20, 2002
First Named Inventor	Ahn, Kie
Group Art Unit	2818
Examiner Name	Wille, Douglas

Sheet 1 of 1

Attorney Docket No: 1303.046US1

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*Douglas Wille*

DATE CONSIDERED

*24 Jan 05*

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Application Number	10/081439
Filing Date	February 20, 2002
First Named Inventor	Ahn, Kie
Group Art Unit	2818
Examiner Name	Unknown

Sheet 1 of 1

Attorney Docket No: 01303.046US1

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*Douglas Wette*

DATE CONSIDERED

*24 June 05*

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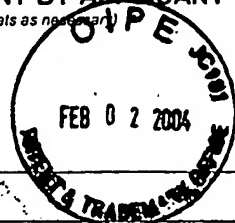
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Application Number 10/081439

Filing Date February 20, 2002

First Named Inventor Ahn, Kie

Group Art Unit 2818

Examiner Name Unknown

Sheet 1 of 2

Attorney Docket No: 1303.046US1

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*Douglas Cottle*

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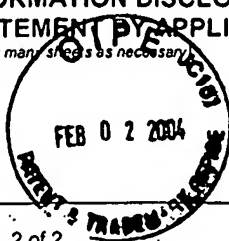
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Application Number 10/081439

Filing Date February 20, 2002

First Named Inventor Ahn, Kie

Group Art Unit 2818

Examiner Name Unknown

Sheet 2 of 2

Attorney Docket No: 1303.046US1

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*Douglas Wells*

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